

**DATA-2011: IEEE INTERNATIONAL WORKSHOP on  
DEFECT & ADAPTIVE TEST ANALYSIS**  
Will be held in conjunction with ITC 2011, Sept. 22-23,  
Disneyland Hotel, Anaheim, CA, USA

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**2011**

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**CALL FOR PAPERS AND PARTICIPATION**

New initiatives in getting more out of testing have opened up new avenues of research and development in the areas of extracting information about defects and IC behavior through the use of innovative analysis techniques. As the need for these novel processes is becoming more widely accepted in the industry, new questions about how these techniques should be executed and controlled in production, the types and sizes of database requirements, and even the format of test data and storage itself are being reviewed and discussed. New issues such as the control and documentation of dynamic test changes in response to local test data, ensuring high quality levels without test escapes, and the practical and realistic limitations of these new ideas are for board/system are now being discussed by many people in the industry. Even the definition of what is “Adaptive testing” is still being reviewed and defined. Closing the knowledge gap about these issues, the process, new test techniques, database requirements, and how defect models are being used to adapt test flows will be the goals of this year’s DATA workshop.

The IEEE International Workshop on Defect & Adaptive Test Analysis (DATA 2011) is aimed at addressing the above issues. Paper presentations on topics related to the topics listed below are expected to generate active discussion on the challenges that must be met to ensure high IC quality through the end of the decade.

**Outlier Identification**

Data-Driven Testing (DDT)

Test Data Analysis

Yield Learning and Analysis Using DDT

Adaptive Test Database requirements

Data-Mining Methods for Test Data Processing

High/Low Voltage Testing & Stress Testing

Transition and Delay Fault Testing

**Reliability and Yield**

Nanometer Test Challenges

Defect Coverage & Metrics

Mixed Current/Voltage Testing

Economics of Defect Based Testing

Fault Localization & Diagnosis

Noise and Crosstalk Testing

In-System or On-board Testing

To present at the workshop, submit a PDF version of an extended abstract of at least 1000 words or a full paper (Max 8 pages, double column, 11pt font size, IEEE proceeding format) by **July 21, 2011**. Each submission should include full name and address of each author, affiliation, telephone number, FAX and Email address. Camera-ready papers for inclusion in the digest of papers will be due on **Aug 30, 2011**. Presentations on cutting edge test technology, innovative test ideas, and industrial practices and experience are welcome. Proposals for Embedded Tutorials, Debates, Panel Discussions or “Spot-Light” presentations describing industrial experiences are also invited.

**AUTHOR’S SCHEDULE:**

**Submission of Extended Abstract:**

**July 21, 2011**

**Notification of Acceptance:**

**August 10, 2011**

**Camera Ready Paper:**

**August 30, 2011**

**Technical Program Submissions:**

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Visit 2011 web-site at: <http://DATA.tttc-events.org/>

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